

2005 USERS' CONFERENCE

10/13 – 10/15
Shanghai, China

UTC
50977 Drakes Bay Dr.
Novi, MI 48374
USA
Phone: (734) 717-7380
Fax: (248) 348-2506
Email: sales@ultitechcorp.com

UTC Beijing Office
Building F, Suite 2101
Tong Dian Ming Ju
1 Tongzhou Baiyuan Rd.
Beijing, China 101100
Tel: + 86 (10) 58884345
Email: beijing@ultitechcorp.com

UTC Shanghai Office
Huai Hai China Tower, Suite 718
889 Renmin Rd.,
Shanghai, China 200010
Tel: +86 (21) 50893530, 50893531
Fax: 86 (21) 50893532
Email: shanghai@ultitechcorp.com

INTRODUCTION

- **Dave Stein**, President & Chief Operating Officer, Denton Inc.
- **Gerhard Haas**, Head, Worldwide Sales, Kayser-Threde GmbH
- **Viktor Singer**, Head, Asian Sales, Kayser-Threde GmbH
- **Christian Ecker**, Head of Software Division, Kayser-Threde GmbH
- **Jim Davidson**, Application Engineer, Kayser-Threde NA, Inc.
- **Brian Coughren**, Vice President, Seattle Safety
- **Rudolf Katzbauer**, Sales Manager, Concept Technologies GmbH
- **Yasuaki Mitsuwa**, Marketing, NAC Image Technology Inc.
- **Dirk Vetter**, Head of Department, IAT

AGENDA

10/14/05

Time	Topic	Presenter	Translator
09:00 - 09:25	Registration		
09:25 - 09:35	Introduction	Jerry Wang UltiTech	
09:35 - 10:20	The nxt Generation of Safety Solutions - Kayser-Threde & Denton's brand new solutions for in-dummy data acquisition	Viktor Singer Kayser-Threde	
10:20 - 11:15	Denton - The Company Created Standard in Safety Measurement	Dave Stein Denton	
11:15 - 11:30	Coffer Break		
11:30 - 12:30	Evaluation Software and Hardware Accessories for Crash	IAT	
12:30 - 13:45	Lunch Break		
13:45 - 14:45	Image Instrumentation For Automotive Testing	Yasuaki Mitsuwa NAC	
14:45 - 15:45	Coffer Break		
15:45 - 16:45	Crash Sled Systems - A Basic Overview of Crash Sled Testing Systems	Brian Coughren Seattle Safety	
16:45 - 17:30	The Application of Safety System in Automotive Testing	Rudolf Katzbauer Concept	
17:30 -	Q & A	Jerry Wang UltiTech	

AGENDA

10/15/05 & 10/16/05

Date	AM	PM
10/15/2005	Visit SMVIC	Technical Exchange
	Technical Exchange	
Date	AM	PM
10/16/2005	F-1 Race	
	Technical Exchange	